


<b>Search Notes</b>  	<b>Application/Control No.</b>  10785177	<b>Applicant(s)/Patent Under Reexamination</b>  SEKII, YASUAKI
	<b>Examiner</b>  TAN X DINH	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner
369	275.3, 275.1, 94	4/16/09	T.D

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (see search history printout)	4/16/09	T.D

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
Interference Search History Printout		4/16/09	T.D

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